

INFORMATION DISCLOSURE
CITATION

ATTY. DOCKET NO.

SERIAL NO.

340-80

10/686,520

APPLICANT

KOCHERGIN et al.

FILING DATE

TC/A.U.

16 October 2003

2872 2883

U.S. PATENT DOCUMENTS

INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>Cmk</i>	4,874,484	10/1989	Foell et al.	438	750	
<i>A</i>	5,262,021	11/1993	V. Lehmann et al.	205	655	
	5,348,627	09/1994	Propst et al.	205	655	
	5,431,766	07/1995	Propst et al.	156	345.15	
	5,544,772	08/1996	Soave et al.	216	2	
	5,645,684	07/1997	Keller	148	33.2	
	5,987,208	11/1999	Grunig	385	146	
	5,997,713	12/1999	Beetz, Jr. et al.	205	124	
	6,521,149	02/2003	Mearini et al.	264	81	
<i>Cmk</i>	6,526,191	02/2003	Geusic et al.	385	14	

FOREIGN PATENT DOCUMENTS

DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
<i>Cmk</i>	3717851	Germany			
<i>Cmk</i>	4202454	Germany			

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

<i>Cmk</i>	Lehmann et al., Optical shortpass filters based on macroporous silicon <i>Appl. Phys. Lett.</i> V 78, N.5, Jan. 2001.
<i>Cmk</i>	J. Schilling et al., "Three-dimensional photonic crystals based on Macroporous silicon with modulated pore diameter", <i>Appl. Phys. Lett.</i> V 78, N.9, Feb. 2001
<i>Cmk</i>	S. Izuo et al., "A novel electrochemical etching technique for n-type silicon," <i>Sensors and Actuators A</i> 97-98 (2002), pp. 720-724
<i>Cmk</i>	A. Vyatkin et al., "Random and Ordered Macropore Formation in p-Type Silicon," <i>J. of the Electrochem. Soc.</i> , 149 (1), pp. G70-G76 (2002)
	H. Föll et. al, "Formation and application of porous silicon", <i>Mat. Sci. Eng. R</i> 39 (2002), pp. 93-141

*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

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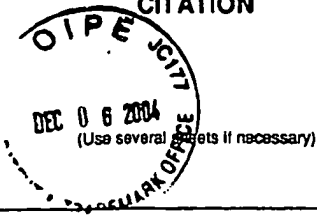
KOCHERGIN et al.

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U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

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✱Examiner

Chris Kalwood

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1-18-05

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BOCHERGIN et al.

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~~SECRET~~ 16 October 2003

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U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

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[illegible]

***Examiner**

Chris Velwood

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